

TEST REPORT ETSI EN 301 489-1 V2.2.3 (2019-11) ETSI EN 301 489-17 V3.2.2 (2019-12)

Report Number	ZKT-2106092453E-3
Date of Test	Jun 10, 2021 to Jun 16, 2021
Date of issue	
Total number of pages	
Test Result	
	Shenzhen ZKT Technology Co., Ltd.
Address	1/E. No. 101. Building B. No. 6. Tangwai Community Industrial
Applicant's name	Kozhtech Technology Co., Ltd
Address	Second Floor, Block B, Jinhui Building, Huaide Community, Humen Town, Dongguan City, Guangdong Province
Manufacturer's name	Kozhtech Technology Co., Ltd
Address	Second Floor, Block B, Jinhui Building, Huaide Community, Humen Town, Dongguan City, Guangdong Province
Test specification:	
Standard	ETSI EN 301 489-1 V2.2.3 (2019-11) ETSI EN 301 489-17 V3.2.2 (2019-12)
Test procedure	1
Non-standard test method	N/A
test (EUT) is in compliance with the only to the tested sample identified	
	ed except in full, without the written approval of ZKT, this document may sonal only, and shall be noted in the revision of the document.
Product name	Wireless Keyboard
Trademark	N/A
Model/Type reference	
DD.	K231,B046,K480
Ratings	: Input: DC 5V 0.5A
4.2V	

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1. Version

Report No.	Issue Date	Description	Approved	
ZKT-2106092453E-3	Jun, 16, 2021	Original	Valid	

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2. TEST SUMMARY

The Product has been tested according to the following specifications:

	EMISSION(EN301489-1,EN30	1489-17)			
Standard	Test Item	Limit	Judgment	Remark	
EN 55020	Conducted Emission	Class B	PASS		
EN 55032	Radiated Emission	Class B	PASS		
EN 61000-3-2	Harmonic Current Emission	Class A or D NOTE (2)	N/A		
EN 61000-3-3	Voltage Fluctuations & Flicker		PASS		
	EMC Immunity				
Section EN 55035	Test Item	Performance Criteria	Judgment	Remark	
EN 61000-4-2	Electrostatic Discharge	В	PASS		
EN 61000-4-3	RF electromagnetic field	А	PASS		
EN 61000-4-4	Fast transients	В	PASS		
EN 61000-4-5	Surges	В	PASS		
EN 61000-4-6	Injected Current	А	PASS		
EN 61000-4-8	Power Frequency Magnetic Field	А	PASS		
EN 61000-4-11	Volt. Interruptions Volt. Dips	B / C / C NOTE (3)	PASS		

NOTE:

- (1)" N/A" denotes test is not applicable in this Test Report
- (2) The power consumption of EUT is less than 75W and no Limits apply.
- (3) Voltage dip: 100% reduction Performance Criteria B
 Voltage dip: 30% reduction Performance Criteria C
 Voltage Interruption: 100% Interruption Performance Criteria C
- (4) For client's request and manual description, the test will not be executed.

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3.1 TEST FACILITY

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3.2 MEASUREMENT UNCERTAINTY

The reported uncertainty of measurement y ± U \cdot where expended uncertainty U is based on a standard uncertainty multiplied by a coverage factor of k=2 \cdot providing a level of confidence of approximately 95 % \circ

No.	Item	Uncertainty
1	3m camber Radiated spurious emission(30MHz-1GHz)	U=4.3dB
2	3m chamber Radiated spurious emission(1GHz-18GHz)	U=4.5dB
3	Conducted Emission (150kHz-30MHz)	U=3.20dB



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4. GENERAL INFORMATION

4.1. GENERAL DESCRIPTION OF EUT

EUT Name	:	Wireless Keyboard
Model No.	:	K230 K231,B046,K480
Serial Model	:	N/A
Model Difference	:	N/A
Trademark	:	N/A
Power supply	:	Input: DC 5V 0.5A
4.2VOperation frequency	:	2402-2480MHz
Modulation	:	GFSK, ∏/4-DQPSK, 8-DPSK
Antenna Type	:	FPCB antenna, Maximum Gain is 0dBi
Intend use environment	:	Residential, commercial and light industrial environment

Note:

1. For a more detailed features description, please refer to the manufacturer's specifications or the User's Manual.

4.2. DESCRIPTION OF TEST MODES

To investigate the maximum EMI emission characteristics generates from EUT, the test system was pre-scanning tested base on the consideration of following EUT operation mode or test configuration mode which possible have effect on EMI emission level. Each of these EUT operation mode(s) or test configuration mode(s) mentioned above was evaluated respectively.

For all Test Mode	Description
Mode 1	Working Mode

4.3. DESCRIPTION OF TEST SETUP

E-1	ĉ
EUT	

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4.4. DESCRIPTION TEST PERIPHERAL AND EUT PERIPHERAL

The EUT has been tested as an independent unit together with other necessary accessories or support units. The following support units or accessories were used to form a representative test configuration during the tests.

Item	Equipment	Mfr/Brand	Model/TypeNo.	Series No.	Note
E-1	Wireless Keyboard	N/A	K230	N/A	EUT
		2			

Item	Shielded Type	Ferrite Core	Length	Note
	55			

Note:

(1) The support equipment was authorized by Declaration of Confirmation.

(2) For detachable type I/O cable should be specified the length in cm in $\[\]$ Length $\]$ column.





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4.5. MEASUREMENT INSTRUMENTS LIST RADIATED TEST SITE

Item	Equipment	Manufacturer	Type No.	Serial No.	Last calibration	Calibrated until
1	Spectrum Analyzer (9kHz-26.5GHz)	KEYSIGHT	9020A	MY45109572	Sep. 22, 2020	Sep. 21, 2021
2	Test Receiver (9kHz-7GHz)	R&S	ESCI7	101169	Sep. 22, 2020	Sep. 21, 2021
3	Bilog Antenna (30MHz-1400MHz)	Schwarzbeck	VULB9168	00877	Sep. 22, 2020	Sep. 21, 2021
4	Horn Antenna (1GHz-18GHz)	SCHWARZBEC K	BBHA9120D	1541	Sep. 22, 2020	Sep. 21, 2021
5	Horn Antenna (18GHz-40GHz)	A.H. System	SAS-574	588	Sep. 22, 2020	Sep. 21, 2021
6	Amplifier (30-1000MHz)	EM Electronics	EM330 Amplifier	N/A	Sep. 22, 2020	Sep. 21, 2021
7	Amplifier (1GHz-40GHz)	全聚达	DLE-161	097	Sep. 22, 2020	Sep. 21, 2021
8	Loop Antenna (9KHz-30MHz)	SCHWARZBEC K	FMZB1519B	014	Sep. 22, 2020	Sep. 21, 2021
9	RF cables1 (9kHz-30MHz)	N/A	9kHz-30MHz	N/A	Sep. 22, 2020	Sep. 21, 2021
10	RF cables2 (30MHz-1GHz)	N/A	30MHz-1GHz	N/A	Sep. 22, 2020	Sep. 21, 2021
11	RF cables3 (1GHz-40GHz)	N/A	1GHz-40GHz	N/A	Sep. 22, 2020	Sep. 21, 2021
12	CMW500 Test	R&S	CMW500	106504	Sep. 22, 2020	Sep. 21, 2021
13	ESG Signal Generator	Agilent	E4421B	GB40051203	Sep. 22, 2020	Sep. 21, 2021
14	Signal Generator	Agilent	N5182A	MY47420215	Sep. 22, 2020	Sep. 21, 2021
			1		1	

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16	Software	Frad	EZ-EMC	FA-03A2 F	FA-03A2 RE		Λ
	ESD		1.4 6.4				1.1.1.1
Item	Kind of Equipment	Manufacturer	Type No.	Serial No.	Last	calibration	Calibrated until
1	ESD TEST GENERATOR	HTEC	HESD16	N/A		Sep. 22, 2020	Sep. 21, 2021

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Item	Kind of Equipment	Manufacturer	Type No.	Serial No.	Last calibration	Calibrated until
1	Signal Generator	R&S	SMT 06	832080/007	Sep. 22, 2020	Sep. 21, 2021
2	Log-Bicon Antenna	Schwarzbeck	VULB9161	4022	Sep. 22, 2020	Sep. 21, 2021
3	Power Amplifier	AR	150W1000M1	320946	Sep. 22, 2020	Sep. 21, 2021
4	Microwave Horn Antenna	AR	AT4002A	321467	Sep. 22, 2020	Sep. 21, 2021
5	Power Amplifier	AR	25S1G4A	308598	Sep. 22, 2020	Sep. 21, 2021

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D.C. Power Supply



5. EMC EMISSION TEST

5.1. CONDUCTED EMISSION MEASUREMENT

5.1.1. POWER LINE CONDUCTED EMISSION (Frequency Range 150KHz-30MHz)

FREQUENCY (MHz)	Class A	(dBuV)	Class B (dBuV)		
	Quasi-peak	Average	Quasi-peak	Average	
0.15 -0.5	79.00	66.00	66 - 56 *	56 - 46 *	
0.50 -5.0	73.00	60.00	56.00	46.00	
5.0 -30.0	73.00	60.00	60.00	50.00	

Note:

- (1) The tighter limit applies at the band edges.
- (2) The limit of " * " marked band means the limitation decreases linearly with the logarithm of the frequency in the range.

The following table is the setting of the receiver

Receiver Parameters	Setting		
Attenuation	10 dB		
Start Frequency	0.15 MHz		
Stop Frequency	30 MHz		
IF Bandwidth	9 kHz		





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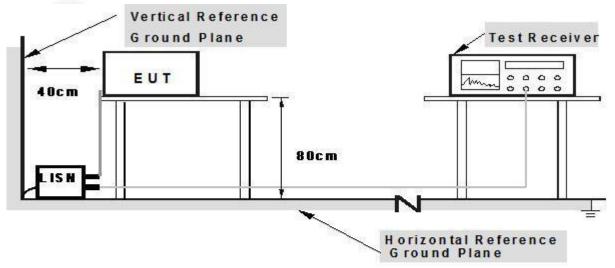
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5.1.2. TEST PROCEDURE

- a. The EUT was placed 0.4 meters from the horizontal ground plane with EUT being connected to the power mains through a line impedance stabilization network (LISN). All other support equipments powered from additional LISN(s). The LISN provide 50 Ohm/ 50uH of coupling impedance for the measuring instrument.
- b. Interconnecting cables that hang closer than 40 cm to the ground plane shall be folded back and forth in the center forming a bundle 30 to 40 cm long.
- c. I/O cables that are not connected to a peripheral shall be bundled in the center. The end of the cable may be terminated, if required, using the correct terminating impedance. The overall length shall not exceed 1 m.
- d. LISN at least 80 cm from nearest part of EUT chassis.
- e. For the actual test configuration, please refer to the related Item -EUT Test Photos.

5.1.3. TEST SETUP



Note: 1.Support units were connected to second LISN. 2.Both of LISNs (ANN) are 80 cm from EUT and at least 80 from other units and other metal planes

5.1.4. EUT OPERATING CONDITIONS

The EUT tested system was configured as the statements of **2.2** Unless otherwise a special operating condition is specified in the follows during the testing.

5.1.5. TEST RESULTS

The EUT is powered bu DC only the test items is not applicabble.

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RADIATED EMISSION MEASUREMENT 5.2.

5.2.1. LIMITS OF RADIATED EMISSION MEASUREMENT

(Below 1000MHz)

	Class A (at 10m)	Class B (at 10m)
FREQUENCY (MHz)	dBuV/m	dBuV/m
30 – 230	40	30
230 – 1000	47	37
5.2.2. LIMITS OF RADIATE	D EMISSION MEASUREMENT	(Above 1000MHz)

LIMITS OF RADIATED EMISSION MEASUREMENT 5.2.2.

	Class A (at 1	0m) dBuV/m	Class B (at 10m) dBuV/m		
FREQUENCY (MHz)	Peak	Avg	Peak	Avg	
1000-3000	76	56	70	50	
3000-6000	80	60	74	54	

Notes:

- (1) The limit for radiated test was performed according to as following: CISPR 22/ FCC PART 15B /ICES-003.
- (2) The tighter limit applies at the band edges.
- (3) Emission level (dBuV/m)=20log Emission level (uV/m).

5.2.3. TEST PROCEDURE

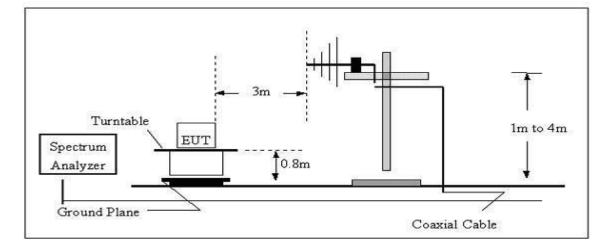
- a. The measuring distance of at 10 m shall be used for measurements at frequency up to 1GHz. For frequencies above 1GHz, any suitable measuring distance may be used.
- b. The EUT was placed on the top of a rotating table 0.8 meters above the ground at a 10 meter open area test site. The table was rotated 360 degrees to determine the position of the highest radiation.
- c. The height of the equipment or of the substitution antenna shall be 0.8 m; the height of the test antenna shall vary between 1 m to 4 m. Both horizontal and vertical polarizations of the antenna are set to make the measurement.
- d. The initial step in collecting conducted emission data is a spectrum analyzer peak detector mode pre-scanning the measurement frequency range. Significant peaks are then marked and then Quasi Peak detector mode re-measured.
- e. If the Peak Mode measured value compliance with and lower than Quasi Peak Mode Limit, the EUT shall be deemed to meet QP Limits and then no additional QP Mode measurement performed.
- f. For the actual test configuration, please refer to the related Item -EUT Test Photos.

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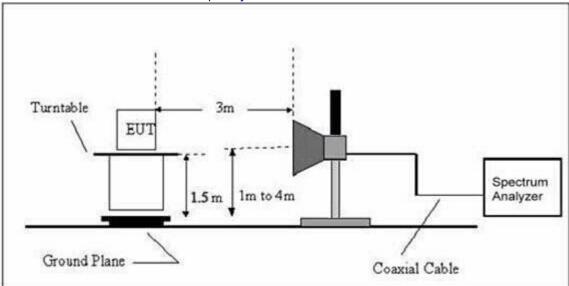


5.2.4. TEST SETUP



(A) Radiated Emission Test Set-Up, Frequency Below 1000MHz

(B) Radiated Emission Test Set-UP Frequency Over 1GHz



5.2.5. EUT OPERATING CONDITIONS

The EUT tested system was configured as the statements of 2.2 Unless otherwise a special

operating condition is specified in the follows during the testing.

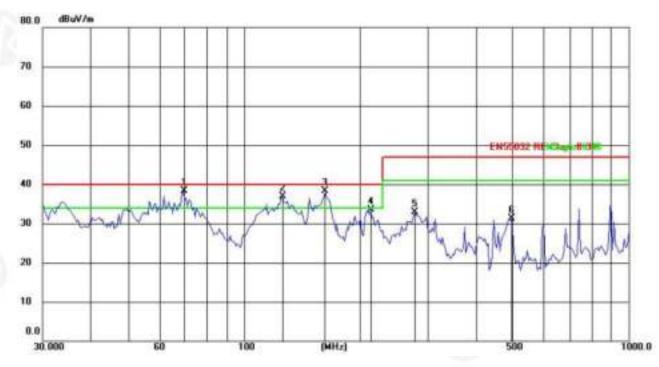
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5.2.6. TEST RESULTS (30-1000MHz)

Temperature :	24 ℃	Relative Humidity :	54%
Pressure :	1010 hPa	Polarization :	Horizontal
Test Voltage :	AC 230V/50Hz	Test Mode :	Mode 1

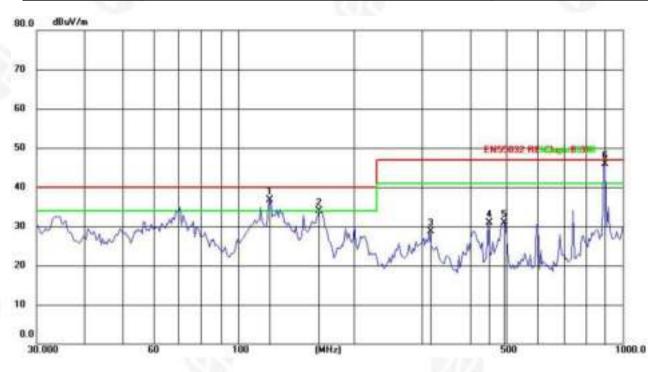


No.	Frequency (MHz)	Reading (dBuV)	Factor (dB/m)	Level (dBuV/m)	Limit (dBuV/m)	Margin (dB)	Detector	Height (cm)	Azimuth (deg.)	P/F	Remark
1	69,6005	55.00	-16.79	38.21	40.00	-1.79	QP				
2	125,2260	55.21	-18.40	36.81	40.00	-3,19	QP				
3	162.8959	55.38	-17.05	38.33	40.00	-1.67	QP				
4	213.7634	52.74	-19.24	33.50	40.00	-6,50	QP				
5	278.0668	49.14	-16.24	32.90	47.00	+14.10	QP				
6	491,6059	45.29	-14.04	31.25	47.00	-15.75	QP				

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Temperature :	24 ℃	Relative Humidity :	54%
Pressure :	1010 hPa	Polarization :	Vertical
Test Voltage :	AC 230V/50Hz	Test Mode :	Mode 1



No.	Frequency (MHz)	Reading (dBuV)	Factor (dB/m)	Level (dBuV/m)	Limit (dBuV/m)	Margin (dB)	Detector	Height (cm)	Azimuth (deg.)	P/F	Remark
1	120.9109	58.19	-21.56	36.63	40.00	-3.37	QP				
2	162.8959	54.61	-20.76	33.85	40.00	-6.15	QP				
3	314.3765	48.59	-19.86	28.73	47.00	-18.27	QP				
4	448.4141	46.32	-15.43	30.89	47.00	-16.11	QP				
5	487.3151	44.89	-14.02	30.87	47.00	-18,13	QP				
6	892.2909	48.82	-2.96	45.88	47.00	-1.14	QP				

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5.3. LIMITS OF HARMONICS CURRENT

		IEC 5	55-2		
	Table -	1		Table -	- 11
Equipment Category	Harmonic Order n	Max. Permissible Harmonic Current (in Ampers)	Equipment Category	Harmonic Order n	Max. Permissible Harmonic Current (in Ampers)
	Odd	Harmonics		Odd	Harmonics
	3	2.30	1 1	3	0.80
	5	1.14		5	0.60
	7	0.77	97.452m	7	0.45
Non	9	0.40	TV	9	0.30
Portable	11	0.33	Receivers	11	0.17
Tools	13	0.21	1.1221000000000000000000000000000000000	13	0.12
or	15⊴n≤39	0.15 · 15/n		15≤n≤39	0.10 · 15/n
TV	Even	Harmonics	1 11	Even Harmonics	
Receivers	2	1.08		2	0.30
	4	0.43		4	0.15
	8	0.30		0.57	110000
	8≤n≤40	0.23 · 8/n		DC	0.05

	EN 6	1000-3-2/IEC	61000-3-2		
Equipment Category	Max. Permissible Harmonic Current (in Ampers)	Equipment Category	Harmonic Order n	Max. Pern Harmonic (in A)	
Class A	Same as Limits	Class D	3 5 7 9 11 13≤n≤39 only o	2.30 1.14 0.77 0.40 0.33 see Table I dd harmonics re	3.4 1.9 1.0 0.5 0.35 3.85/n equired



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5.3.1. TEST PROCEDURE

a. The EUT was placed on the top of a wooden table 0.8 meters above the ground and operated to produce the maximum harmonic components under normal operating conditions.b. The classification of EUT is according to section 5 of EN 61000-3-2: 2000. The EUT is classified as follows:

Class A: Balanced three-phase equipment, Household appliances excluding equipment as Class D, Tools excluding portable tools, Dimmers for incandescent lamps, audio equipment, equipment not specified in one of the three other classes.

Class B: Portable tools. Portable tools.; Arc welding equipment which is not professional equipment.

Class C: Lighting equipment.

Class D: Equipment having a specified power less than or equal to600 W of the following types: Personal computers and personal computer monitors and television receivers.

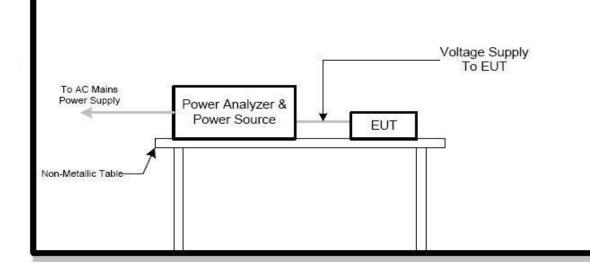
c. The correspondent test program of test instrument to measure the current harmonics emanated from EUT is chosen. The measure time shall be not less than the time necessary for the EUT to be exercised.

d. For the actual test configuration, please refer to the related item -EUT Test Photos.

5.3.2. EUT OPERATING CONDITIONS

The EUT tested system was configured as the statements of **2.2** Unless otherwise a special operating condition is specified in the follows during the testing.

5.3.3. TEST SETUP



5.3.4. TEST RESULTS

The EUT is powered bu DC only the test items is not applicabble.



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5.4. VOLTAGE FLUCTUATION AND FLICKERS

5.4.1. LIMITS OF VOLTAGE FLUCTUATION AND FLICKERS

Tests	Li	mits	Descriptions	
Tests	IEC555-3	IEC/EN 61000-3-3	Descriptions	
Pst	≤ 1.0, Tp= 10 min.	≤ 1.0, Tp= 10 min.	Short Term Flicker Indicator	
Plt	N/A	≤ 0.65, Tp=2 hr.	Long Term Flicker Indicator	
dc	≤ 3%	≤ 3.3%	Relative Steady-State V-Chang	
dmax	≤4%	≤ 4%	Maximum Relative V-change	
d (t)	N/A	\leq 3.3% for > 500 ms	Relative V-change characteristic	

5.4.2 TEST PROCEDURE

a. Harmonic Current Test:

Test was performed according to the procedures specified in Clause 5.0 of IEC555-2 and/or Sub-clause 6.2 of IEC/EN 61000-3-2 depend on which standard adopted for compliance measurement.

b. Fluctuation and Flickers Test:

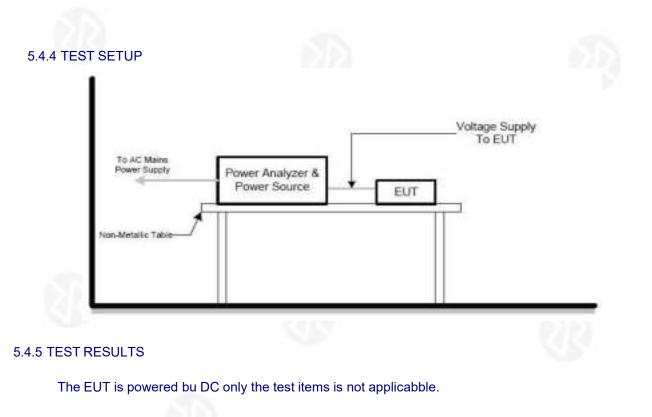
Tests was performed according to the Test Conditions/Assessment of Voltage Fluctuations specified in Clause 5.0/6.0 of IEC555-3 and/or Clause 6.0/4.0 of IEC/EN 61000-3-3 depend on which standard adopted for compliance measurement.

c. All types of harmonic current and/or voltage fluctuation in this report are assessed by direct measurement using flicker-meter.

d. For the actual test configuration, please refer to the related Item -EUT Test Photos.

5.4.3 EUT OPERATING CONDITIONS

The EUT tested system was configured as the statements of **2.2** Unless otherwise a special operating condition is specified in the follows during the testing.



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6. EMC IMMUNITY TEST

6.1. GENERAL PERFORMANCE CRITERIA

PERFORMANCE CRITERIA

According To EN 301489-17 standard, The General Performance Criteria As Following:

Criteria	During the test	After the test
A	Shall operate as intended May show degradation of performance (see note 1) Shall be no loss of function Shall be no unintentional transmissions	Shall operate as intended Shall be no degradation of performance (see note 2) Shall be no loss of function Shall be no loss of stored data or user programmable functions
в	May show loss of function (one or more) May show degradation of performance (see note 1) No unintentional transmissions	Functions shall be self-recoverable Shall operate as intended after recovering Shall be no degradation of performance (see note 2) Shall be no loss of stored data or user programmable functions
с	May be loss of function (one or more)	Functions shall be recoverable by the operator Shall operate as intended after recovering Shall be no degradation of performance (see note 2)

NOTE 1: Degradation of performance during the test is understood as a degradation to a level not below a minimum performance level specified by the manufacturer for the use of the apparatus as intended. In some cases the specified minimum performance level may be replaced by a permissible degradation of performance. If the minimum performance level or the permissible performance degradation is not specified by the manufacturer then either of these may be derived from the product description and documentation (including leaflets and advertising) and what the user may reasonably expect from the apparatus if used as intended.

NOTE 2: no degradation of performance after the test is understood as any degradation below a minimum performance level specified by the manufacturer for the use of the apparatus as intended. In some cases the specified minimum performance level may be replaced by a permissible degradation of performance. After the test no change of actual operating data or user retrievable data is allowed. If the minimum performance level or the permissible performance degradation is not specified by the manufacturer then either of these may be derived from the product description and documentation (including leaflets and advertising) and what the user may reasonably expect from the apparatus if used as intended.







PERFORMANCE FOR TT

The performance criteria B shall apply, except for voltage dips of 100 ms and voltage interruptions of 5 000 ms duration, for which performance criteria C shall apply. Tests shall be repeated with the EUT in standby mode (if applicable) to ensure that unintentional transmission does not occur. In systems using acknowledgement signals, it is recognized that an acknowledgement (ACK) or not-acknowledgement (NACK) transmission may occur, and steps should be taken to ensure that any transmission resulting from the application of the test is correctly interpreted.

PERFORMANCE FOR TR

The performance criteria B shall apply, except for voltage dips of 100 ms and voltage interruptions of 5 000 ms duration for which performance criteria C shall apply. Where the EUT is a transceiver, under no circumstances, shall the transmitter operate unintentionally during the test. In systems using acknowledgement signals, it is recognized that an ACK or NACK transmission may occur, and steps should be taken to ensure that any transmission resulting from the application of the test is correctly interpreted.

PERFORMANCE FOR CT

The performance criteria A shall apply. Tests shall be repeated with the EUT in standby mode (if applicable) to ensure that unintentional transmission does not occur. In systems using acknowledgement signals, it is recognized that an Acknowledgement (ACK) or Not Acknowledgement (NACK) transmission may occur, and steps should be taken to ensure that any transmission resulting from the application of the test is correctly interpreted.

PERFORMANCE FOR CR

The performance criteria A shall apply. Where the EUT is a transceiver, under no circumstances, shall the transmitter operate unintentionally during the test. In systems using acknowledgement signals, it is recognized that an ACK or NACK transmission may occur, and steps should be taken to ensure that any transmission resulting from the application of the test is correctly interpreted.

6.2. GENERAL PERFORMANCE CRITERIA TEST SETUP

The EUT tested system was configured as the statements of **2.2** Unless otherwise a special operating condition is specified in the follows during the testing.

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7. ESD TESTING

7.1 TEST SPECIFICATION

IEC/EN 61000-4-2
330 ohm / 150 pF
В
Air Discharge:2kV/4kV/8kV (Direct)
Contact Discharge : 2kV/4kV (Direct/Indirect)
Positive & Negative
Air Discharge: min. 20 times at each test point
Contact Discharge: min. 200 times in total
AC Discharge
1 second minimum

7.2 TEST PROCEDURE

The test generator necessary to perform direct and indirect application of discharges to the EUT in the following manner:

a. Contact discharge was applied to conductive surfaces and coupling planes of the EUT. During the test, it was performed with single discharges. For the single discharge time between successive single discharges was at least 1 second. The EUT shall be exposed to at least 200 discharges, 100 each at negative and positive polarity, at a minimum of four test points. One of the test points shall be subjected to at least 50 indirect discharges to the center of the front edge of the horizontal coupling plane. The remaining three test points shall each receive at least 50 direct contact discharges.

If no direct contact test points are available, then at least 200 indirect discharges shall be applied in the indirect mode. Test shall be performed at a maximum repetition rate of one discharge per second. Vertical Coupling Plane (VCP):

The coupling plane, of dimensions $0.5m \times 0.5m$, is placed parallel to, and positioned at a distance 0.1m from, the EUT, with the Discharge Electrode touching the coupling plane.

The four faces of the EUT will be performed with electrostatic discharge.

Horizontal Coupling Plane (HCP):

The coupling plane is placed under to the EUT. The generator shall be positioned vertically at a distance of 0.1m from the EUT, with the Discharge Electrode touching the coupling plane. The four faces of the EUT will be performed with electrostatic discharge.

- b. Air discharges at insulation surfaces of the EUT.
- It was at least ten single discharges with positive and negative at the same selected point.
- c. For the actual test configuration, please refer to the related Item -EUT Test Photos.



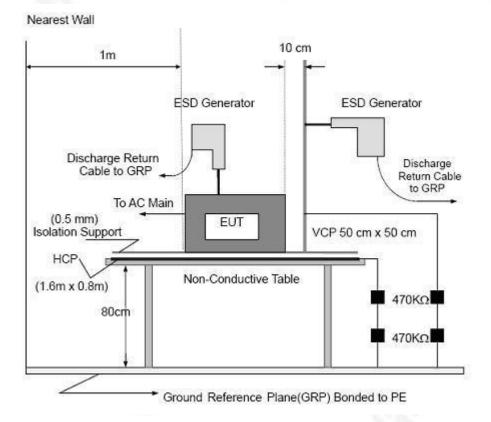
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7.3 TEST SETUP



Note:

TABLE-TOP EQUIPMENT

The configuration consisted of a wooden table 0.8 meters high standing on the Ground Reference Plane. The GRP consisted of a sheet of aluminum at least 0.25mm thick, and 2.5 meters square connected to the protective grounding system. A Horizontal Coupling Plane (1.6m x 0.8m) was placed on the table and attached to the GRP by means of a cable with 940k total impedance. The equipment under test, was installed in a representative system as described in section 7 of IEC /EN 61000-4-2, and its cables were placed on the HCP and isolated by an insulating support of 0.5mm thickness. A distance of1-meter minimum was provided between the EUT and the walls of the laboratory and any other metallic structure.

FLOOR-STANDING EQUIPMENT

The equipment under test was installed in a representative system as described in section 7 of IEC/EN 61000-4-2, and its cables were isolated from the Ground Reference Plane by an insulating support of0.1-meter thickness. The GRP consisted of a sheet of aluminum that is at least 0.25mm thick, and 2.5meters square connected to the protective grounding system and extended at least 0.5 meters from the EUT on all sides.









7.4 TEST RESULTS

Temperature :	25 ℃	Relative Humidity :	45%
Pressure :	1010 hPa	Test Power :	DC 3.7V Battery
Test Mode	Mode 1		

Mode	Air Discharge					Contact Discharge						ge	Obser						
Test level (kV)	2	2	4	4	8	3	1	0	2	2	4	1	(6	8	3	vation	Criterion	Result
Test Location	+	-	+	-	+	-	+	-	+	-	+	-	+	-	+	-			
HCP	s.																		PASS
VCP									Α	Α	Α	Α							PASS
USB port									Α	А	А	А						1.1	PASS
enclosure	Α	Α	Α	Α	Α	Α											TT,TR	T,TR B	PASS
slot	Α	А	Α	Α	Α	Α													PASS
Button	Α	Α	Α	Α	Α	Α													PASS

Note:

- 1) P/N denotes the Positive/Negative polarity of the output voltage.
- 2) Test condition:

Direct / Indirect (HCP/VCP) discharges: Minimum 50 times (Positive/Negative) at each point. Air discharges: Minimum 10 times (Positive/Negative) at each point.

- 3) N/A denotes test is not applicable in this test report
- 4)There was not any unintentional transmission in standby mode

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8. RS TESTING

8.1 TEST SPECIFICATION

IEC/EN 61000-4-3
Α
80 MHz - 6000 MHz
3 V/m
1kHz Sine Wave, 80%, AM Modulation
1 % of fundamental
Horizontal and Vertical
3 m
0.8 m
at least 3 seconds



















8.2 TEST PROCEDURE

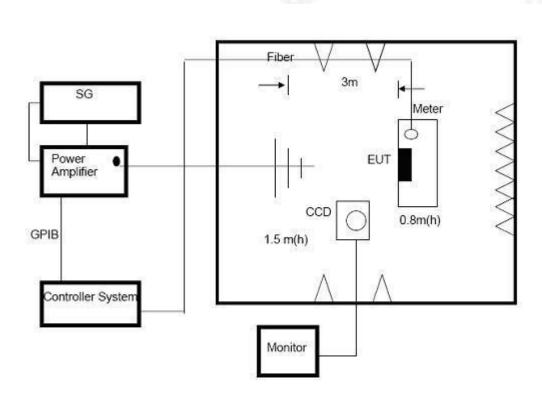
The EUT and support equipment, which are placed on a table that is 0.8 meter above ground and the testing was performed in a fully-anechoic chamber.

The testing distance from antenna to the EUT was 3 meters.

The other condition as following manner:

- a. The field strength level was 3V/m.
- b. The frequency range is swept from 80 MHz to 6000 MHz, & 1400MHz 2700MHz with the signal 80% amplitude modulated with a 1kHz sine wave. The rate of sweep did not exceed 1.5x 10-3 decade/s. Where the frequency range is swept incrementally, the step size was 1% of fundamental.
- c. Sweep Frequency 900 MHz, with the Duty Cycle:1/8 and Modulation: Pulse 217 Hz(if applicable)
- d. The dwell time at each frequency shall be not less than the time necessary for the EUT to be able to respond.
- e. The test was performed with the EUT exposed to both vertically and horizontally polarized fields on each of the four sides.
- f. For the actual test configuration, please refer to the related Item -EUT Test Photos.

8.3 TEST SETUP



Note:

TABLE-TOP EQUIPMENT

The EUT installed in a representative system as described in section 7 of IEC/EN 61000-4-3 was placed on a non-conductive table 0.8 meters in height. The system under test was connected to the power and signal wire according to relevant installation instructions.

FLOOR-STANDING EQUIPMENT

The EUT installed in a representative system as described in section 7 of IEC/EN 61000-4-3 was placed on a non-conductive wood support 0.1 meters in height. The system under test was connected to the power and signal wire according to relevant installation instructions.

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8.4 TEST RESULTS

Temperature :	25 ℃	Relative Humidity :	45%
Pressure :	1010 hPa	Test Power :	DC 3.7V Battery
Test Mode	Mode 1		

Frequency Range (MHz)	RF Field Position	R.F. Field Strength	Azimuth	Observation	Perform. Criteria	Results	Judgment
			Front				
80~6000	H/V	3 V/m (rms) AM Modulated	Rear	CT,CR	Α	Α	PASS
80~0000	117 V	1000Hz, 80%	Left	CI,CK	~	^	FASS
			Right				44

Note:

- 1) P/N denotes the Positive/Negative polarity of the output voltage.
- 2) N/A denotes test is not applicable in this test report.
- 3) There was no change operated with initial operating during the test.
- 4) There was not any unintentional transmission in standby mode







9. EFT/BURST TESTING

9.1 TEST SPECIFICATION

IEC/EN 61000-4-4
В
Power Line:1 kV
Signal/Control Line: 0.5 KV
Positive & Negative
5 kHz
5/50 ns
15 ms
300 ms
Not less than 1 min.

9.2 TEST PROCEDURE

The EUT and support equipment, are placed on a table that is 0.8 meter above a metal ground plane measured 1m*1m min. and 0.65mm thick min.

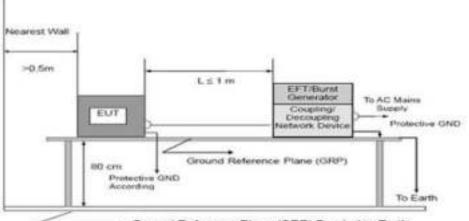
- The other condition as following manner:
- a. The length of power cord between the coupling device and the EUT should not exceed 1 meter.
- b. Both positive and negative polarity discharges were applied.
- c. The duration time of each test sequential was 1 minute
- d. For the actual test configuration, please refer to the related Item -EUT Test Photos.



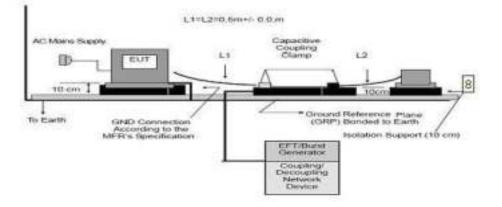








- Ground Reference Plane (GRP) Bonded to Earth



Note:

TABLE-TOP EQUIPMENT

The configuration consisted of a wooden table (0.8m high) standing on the Ground Reference Plane. The GRP consisted of a sheet of aluminum (at least 0.25mm thick and 2.5m square) connected to the protective grounding system. A minimum distance of 0.5m was provided between the EUT and the walls of the laboratory or any other metallic structure.

FLOOR-STANDING EQUIPMENT

The EUT installed in a representative system as described in section 7 of IEC/EN 61000-4-4 and its cables, were isolated from the Ground Reference Plane by an insulating support that is 0.1-meter thick. The GRP consisted of a sheet of aluminum (at least 0.25mm thick and 2.5m square) connected to the protective grounding system.

9.4 TEST RESULTS

The EUT is powered bu DC only the test items is not applicabble.



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10. SURGE TESTING

10.1 TEST SPECIFICATION

Basic Standard:	IEC/EN 61000-4-5
Required Performance	В
Wave-Shape:	Combination Wave
	1.2/50 us Open Circuit Voltage
	8 /20 us Short Circuit Current
Test Voltage:	Power Line: 0.5 kV, 1 kV, 2 kV
Surge Input/Output:	L1-A1, A2, A3, A4, A5, A6, A7, L1-PE, A1, A2, A3,
	A4, A5, A6, A7-PE
Generator Source:	2 ohm between networks
Impedance:	12 ohm between network and ground
Polarity:	Positive/Negative
Phase Angle:	0 /90/180/270
Pulse Repetition Rate:	1 time / min. (maximum)
Number of Tests:	5 positive and 5 negative at selected points



a. For EUT power supply:

The surge is to be applied to the EUT power supply terminals via the capacitive coupling network. Decoupling networks are required in order to avoid possible adverse effects on equipment not under test that may be powered by the same lines, and to provide sufficient decoupling impedance to the surge wave. The power cord between the EUT and the coupling/decoupling networks shall be 2meters in length (or shorter).

b. For test applied to unshielded unsymmetrically operated interconnection lines of EUT:

The surge is applied to the lines via the capacitive coupling. The coupling /decoupling networks shall not influence the specified functional conditions of the EUT. The interconnection line between the EUT and the coupling/decoupling networks shall be 2 meters in length (or shorter).

- c. For test applied to unshielded symmetrically operated interconnection /telecommunication lines of EUT: The surge is applied to the lines via gas arrestors coupling. Test levels below the ignition point of the coupling arrestor cannot be specified. The interconnection line between the EUT and the coupling/decoupling networks shall be 2 meters in length (or shorter).
- d. For the actual test configuration, please refer to the related Item -EUT Test Photos.



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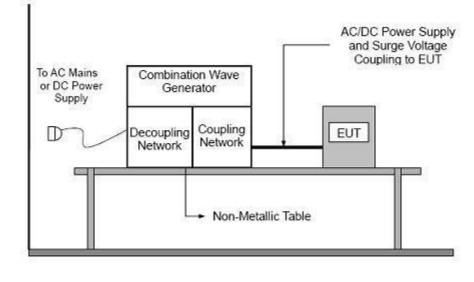




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10.3 TEST SETUP





10.4 TEST RESULTS

The EUT is powered bu DC only the test items is not applicabble.





11. INJECTION CURRENT TESTING

11.1 TEST SPECIFICATION

Basic Standard:	IEC/EN 61000-4-6
Required Performance	Α
Frequency Range:	0.15 MHz - 80 MHz
Field Strength:	3 Vr.m.s.
Modulation:	1kHz Sine Wave, 80%, AM Modulation
Frequency Step:	1 % of fundamental
Dwell Time:	at least 3 seconds

11.2 TEST PROCEDURE

The EUT and support equipment, are placed on a table that is 0.8 meter above a metal ground plane measured 1m*1m min. and 0.65mm thick min. The other condition as following manner:

- a. The field strength level was 3V.
- b. The frequency range is swept from 150 KHz to 80 MHz, with the signal 80% amplitude modulated with a 1kHz sine wave. The rate of sweep did not exceed 1.5x 10-3 decade/s. Where the frequency range is swept incrementally, the step size was 1% of fundamental.
- c. The dwell time at each frequency shall be not less than the time necessary for the EUT to be able to respond.
- d. For the actual test configuration, please refer to the related Item -EUT Test Photos.

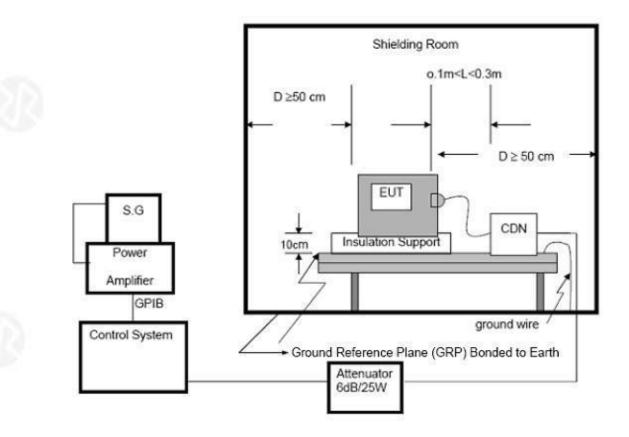
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11.3 TEST SETUP



For the actual test configuration, please refer to the related Item -EUT Test Photos.

NOTE:

FLOOR-STANDING EQUIPMENT

The equipment to be tested is placed on an insulating support of 0.1 meters height above a ground reference plane. All relevant cables shall be provided with the appropriate coupling and decoupling devices at a distance between 0.1 meters and 0.3 meters from the projected geometry of the EUT on the ground reference plane.

11.4 TEST RESULTS

The EUT is powered bu DC only the test items is not applicabble.



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12. VOLTAGE INTERRUPTION/DIPS TESTING

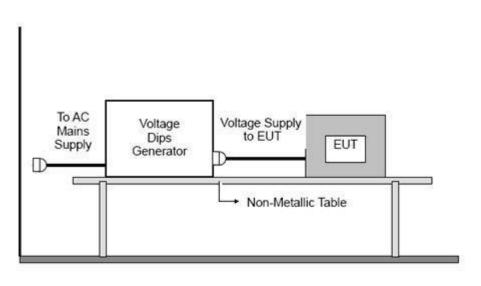
12.1 TEST SPECIFICATION

Basic Standard:	IEC/EN 61000-4-11
Required Performance	100% reduction, 0.5 Cycle
	100% reduction, 1.0 Cycle
	30% reduction, 25 Cycles
Voltage Interruptions:	100% reduction, 250 Cycles
Test Duration Time:	Minimum three test events in sequence
Interval between Event:	Minimum ten seconds
Phase Angle:	0°/45°/90°/135°/180°/225°/270°/315°/360°
Test Cycle:	3 times

12.2 TEST PROCEDURE

The EUT shall be tested for each selected combination of test levels and duration with a sequence of three dips/interruptions with intervals of 10 s minimum (between each test event). Each representative mode of operation shall be tested. Abrupt changes in supply voltage shall occur at zero crossings of the voltage waveform.

12.3 TEST SETUP



For the actual test configuration, please refer to the related Item -EUT Test Photos.

12.4 TEST RESULTS

The EUT is powered bu DC only the test items is not applicabble.

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13. PHOTOS OF TEST SETUP









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14. PHOTOS OF EUT

EUT Photo 1



EUT Photo 2



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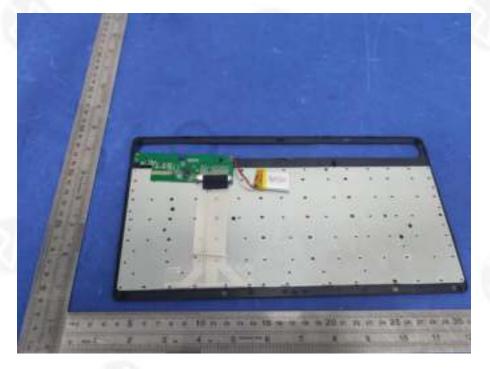
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EUT Photo 3



***** END OF REPORT *****









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